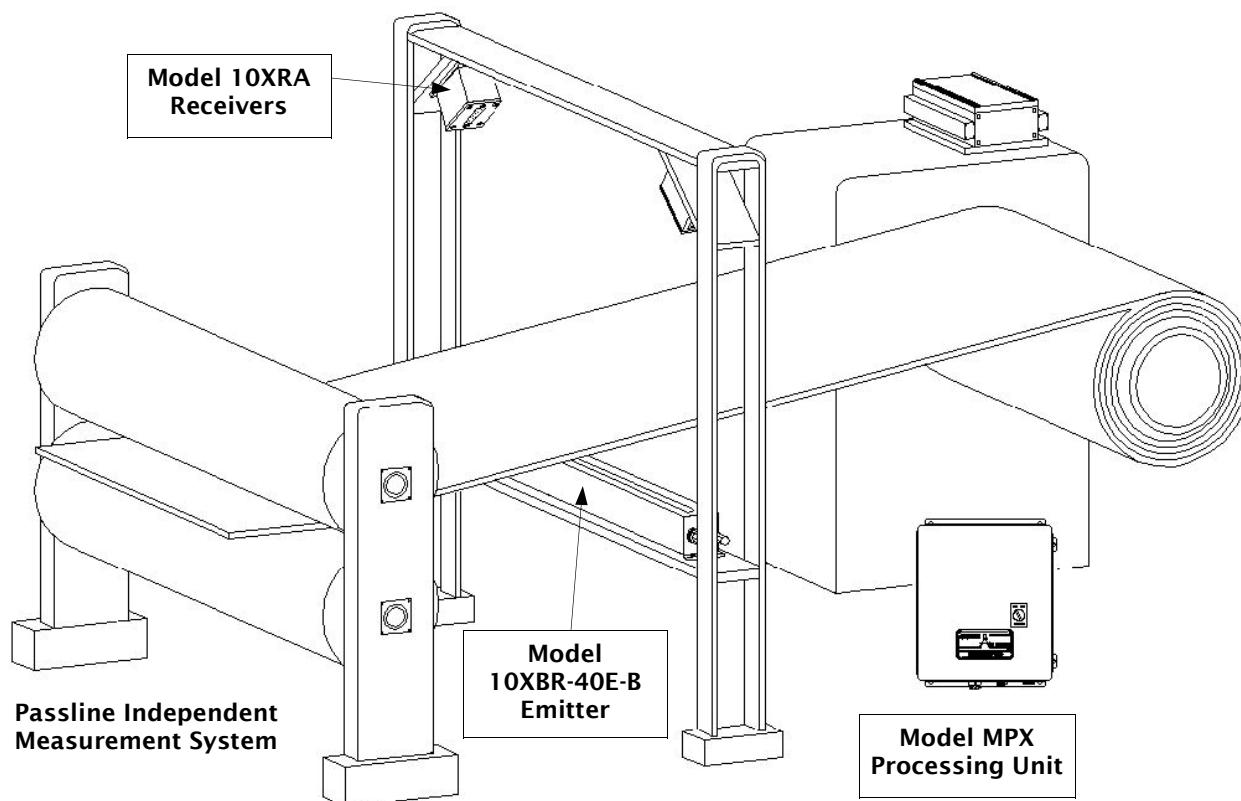


## Passline Independent Measurement System



Accurate measurement is one of the vexing problems found in strip product processing lines having a variable product passline (distance from the bottom of the strip to the top of the emitter). The SCAN-A-LINE™ product development team has recognized the need for dimensional measurement that is completely independent of product passline. This is especially significant near the payoff or rewind mandrels where passline varies as the coil diameter changes. Errors are unavoidable when attempting to measure materials with a varying passline when using any single sensor system. Position errors occur because the edge is viewed by a single point receiver (or camera in a camera-based system). Errors can be calibrated out, but any passline changes after system calibration will result in additional measurement errors in the material dimensions.

The Passline Independent Measurement System (PIM System) solves these difficult variable passline measurement problems with a unique and flexible measurement system utilizing new SCAN-A-LINE™ sensor and processing unit technology.

- **Linearity of 0.024 inch [0.61 mm] @ 2-sigma**
- **Patented Scanned LED Technology**
- **NO MOVING PARTS**
- **Solid State Reliability**
- **No Light Sources to Replace**
- **High, Low and Target Limit Relays**
- **Multiple Analog Outputs Available**
- **Sensor FAULT Output**
- **Serial I/O for Data Output to Computer, Data Logger or Printer (optional)**
- **Several Customer Interfaces Available**
- **Centerline Position Output Available**
- **Custom Software Available**

\* Specifications based on a stable passline. 0.032" with variable passline.



**Harris Instrument Corporation**  
 155 Johnson Drive Delaware, OH 43015  
 Voice: 740-369-3580 Fax: 740-369-2653  
 info@harris-instrument.com www.harris-instrument.com